

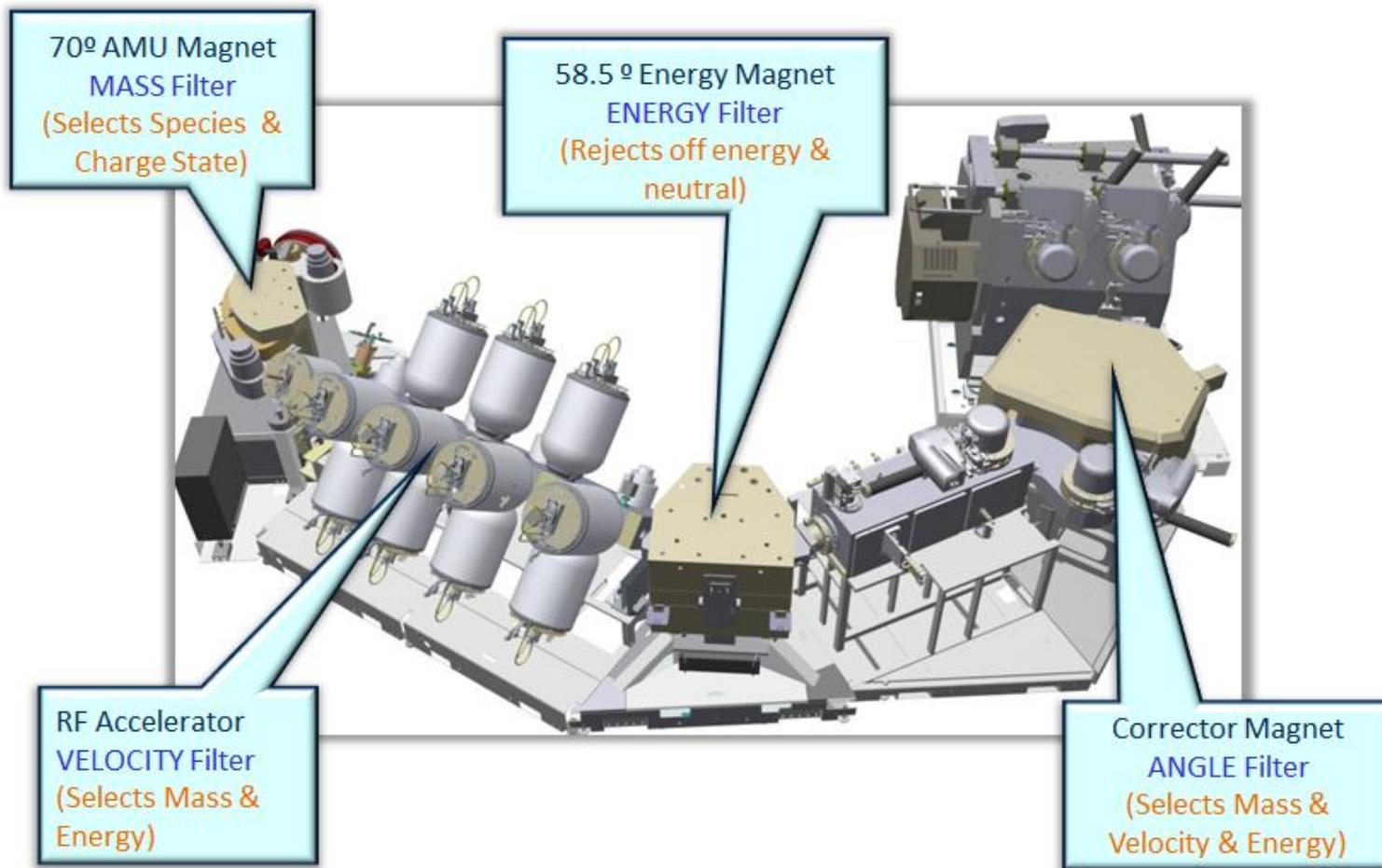


***Purion XE – Purity, Precision, Productivity***

**Industry Leading Beam Purity**

# Purion XE: Industry Leading Contamination Control

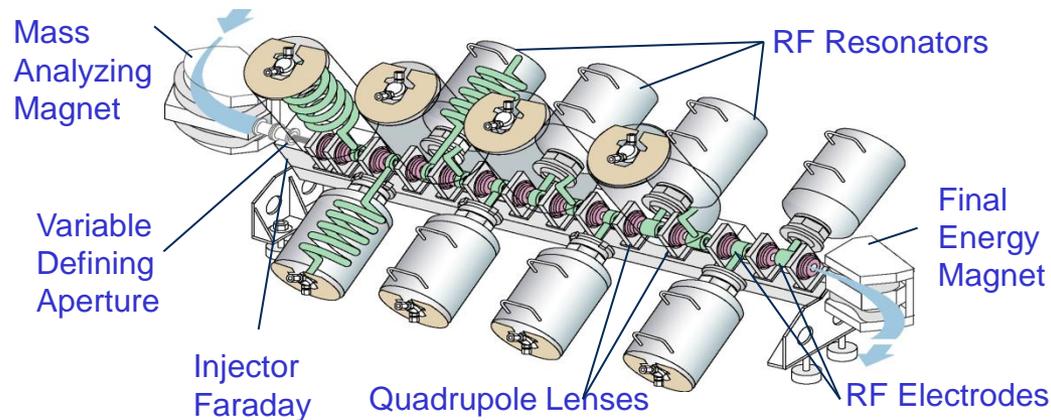
## Multiple Points of Filtration



# Axcelis' High Energy Ion Implanters

## Superior Contamination Control – Beam Purity

- Unmatched beam purity through triple filtration
  - Mass analysis magnet - Mass filter - selects species and charge state
  - Production proven RF Linear Accelerator - Velocity Filter – mass and energy
  - Final Energy magnet - Energy filter - selects final energy and rejects neutrals

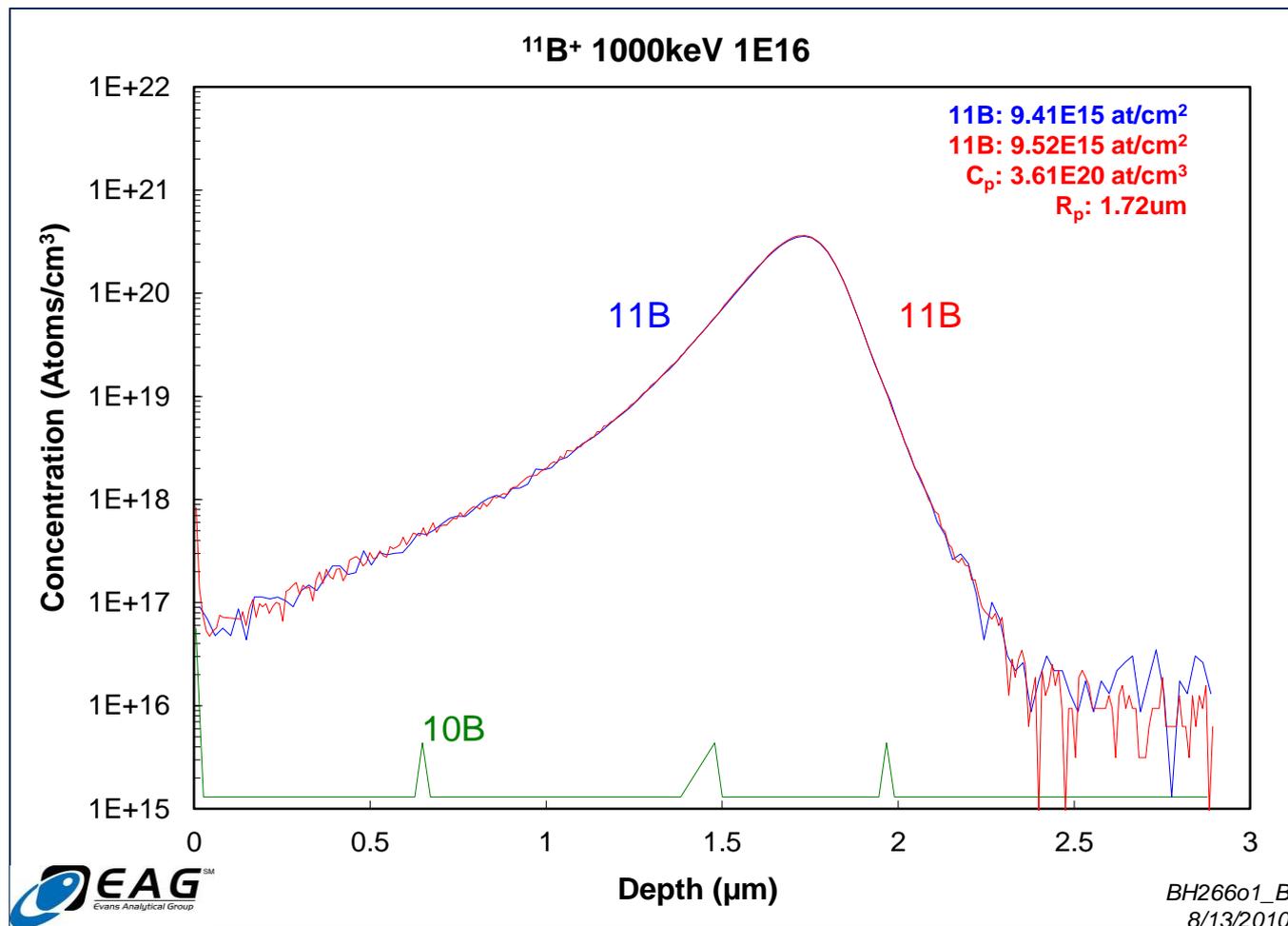


- No energy or foreign species contamination seen at SIMS detection limits
  - Energy contamination < 0.01%
  - Foreign species contamination < 0.001%

# Purion XE Mass Filtering

## No $^{10}\text{B}$ Detected in $^{11}\text{B}^+$ 1000keV 1E16 SIMS

- Source gas: Non-enriched Boron (80%  $^{11}\text{B}$ , 20%  $^{10}\text{B}$ )
- Recipe:  $^{11}\text{B}^+$  1000keV 1e16 implanted on Purion XE
- $^{10}\text{B}$  reduced by > 10,000X from source to wafer, despite a mass difference of only 10%



# Optima XEx Process Advantages

## Unmatched Species Purity

- A 2500 keV P<sup>+++</sup> implant was performed while feeding ~10% non-enriched BF<sub>3</sub> into the arc chamber.
- The <sup>10</sup>B SIMS profile, despite having an extremely low background level, reveals no energetic <sup>10</sup>B contamination in the P<sup>+++</sup> implant.
- The integrated <sup>10</sup>B dose of ~3x10<sup>9</sup> cm<sup>-2</sup> indicates an energetic contamination level of ~ 1 part per million.
- Again, the <sup>31</sup>P SIMS profile is devoid of energy contamination

